UNITED STATES PATENT AND TRADEMARK OFFICE

CONFIRMATION NO. 5475

Bib Data Sheet

SERIAL NUMBER 10/632,273	FILING DATE 07/31/2003 RULE	CLASS 324	GROUP ART UNIT 2829	ATTORNEY DOCKET NO. MI22- 2379

APPLICANTS

Warren M. Farnworth, Nampa, ID;

Malcolm Grief, Boise, ID;

** CONTINUING DATA ***************************
This application is a DIV of 10/057,711 01/24/2002 PAT 6,670,819
which is a DIV of 09/411,139 10/01/1999 PAT 6,657,450
which is a DIV of 09/267,990 03/12/1999 PAT 6,380,754
which is a DIV of 08/895,764 07/17/1997 PAT 6,127,195
which is a CON of 08/621,157 03/21/1996 ABN
which is a CON of 08/206,747 03/04/1994 PAT 5,523,697
which is a DIV of 08/116,394 09/03/1993 PAT 5,326,428

checked the

** FOREIGN APPLICATIONS ********************

None the

IF REQUIRED, FOREIGN FILING LICENSE GRANTED
** 10/28/2003

Foreign Priority claimed ☐ yes ☒ no				
35 USC 119 (a-d) conditions met ☐ yes ☒ no ☐ Met after Allowance		STATE OR COUNTRY ID	SHEETS DRAWING 10	TOTAL CLAIMS 14 28	INDEPENDENT CLAIMS 7 10
Verified and Acknowledged Examiner's Signature Initials		ID	10		

ADDRESS
021567
WELLS ST. JOHN P.S.
601 W. FIRST AVENUE, SUITE 1300
SPOKANE , WA
99201

TITLE
Method and apparatus for testing semiconductor circuitry for operability and method of forming apparatus for testing semiconductor circuitry for operability

		☐ All Fees

FILING FEE	FEES: Authority has been given in Paper	☐ 1.16 Fees (Filing)
RECEIVED	No. _____ to charge/credit DEPOSIT ACCOUNT	☐ 1.17 Fees (Processing Ext. of time)
2526	No. _____ for following:	☐ 1.18 Fees (Issue)
		☐ Other _____
		☐ Credit